

# **Notice of References Cited**

Application/Control No.

10/022,125

Applicant(s)/Patent Under Reexam

Op De Beek et al.

Examiner

Drew A. Dunn

Art Unit

2882

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## **U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
A	5,301,108	4/1994	Hsieh	378	8
B	6,148,057	11/2000	Urchuk et al.	378	207
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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